



TET ESTEL AS
ESTONIA

February
2015

Series
TFI271C-200

Fast Stud Mounted Thyristor
Type TFI271C-200

Low turn-off time
Low reverse recovery charge
Distributed amplified gate for high di/dt

Maximum mean on-state current	I_{TAV}	200 A
Maximum repetitive peak off-state and reverse voltage	U_{DRM} U_{RRM}	800 ÷ 1500 V
Turn-off time	t_q	16; 20; 25; 32 μs
U_{DRM}, U_{RRM}, V	800	900
	1000	1100
	1200	1300
	1400	1500
Voltage code	8	9
	10	11
	12	13
	14	15
$T_{vj}, °C$	- 60 ÷ 125	

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	TFI271C-200	Conditions
I_{TAV}	Mean on-state current	A	200	$T_c=85 °C$, 180° half-sine wave, 50 Hz
I_{TRMS}	RMS on-state current	A	314	$T_c=85 °C$
I_{TSM}	Surge on-state current	kA	6,0 6,6	$T_{vj}=125 °C$ $T_{vj}=25 °C$ tp=10 ms
I^2t	Limiting load integral	kA^2s	180 217	$T_{vj}=125 °C$ $T_{vj}=25 °C$ $U_R=0$
U_{DRM}, U_{RRM}	Repetitive peak off-state and reverse voltage	V	800÷1500	$T_j \min \leq T_{vj} \leq T_{jM}$ 180° half-sine wave, 50 Hz Gate open
U_{DSM}, U_{RSM}	Non-repetitive peak off-state and reverse voltage	V	900÷1600	$T_j \min \leq T_{vj} \leq T_{jM}$ 180° half-sine wave tp=10 ms, Single pulse Gate open
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current : non - repetitive repetitive	$A/\mu s$	1600 800	$T_{vj}=125 °C$; $U_D=0,67 U_{DRM}$, Gate pulse : 10V, 5 Ω, 1 μs rise time, 10 μs
U_{RGM}	Peak reverse gate voltage	V	5	$T_j \min \leq T_{vj} \leq T_{jM}$
T_{stg}	Storage temperature	°C	-60÷80	
T_{vj}	Junction temperature	°C	-60÷125	

CHARACTERISTICS

U_{TM}	Peak on-state voltage	V	2,3	$T_{vj}=25 °C$, $I_{TM}=3,14 I_{TAV}$
$U_{T(TO)}$	Threshold voltage	V	1,45	$T_{vj}=125 °C$
R_T	On-state slope resistance	mΩ	1,5	$1,57 I_{TAV} < I_T < 4,71 I_{TAV}$
I_{DRM} I_{RRM}	Repetitive peak off-state and reverse current	mA	70 70	$T_{vj}=125 °C$, $U_D = U_{DRM}$ $U_R = U_{RRM}$

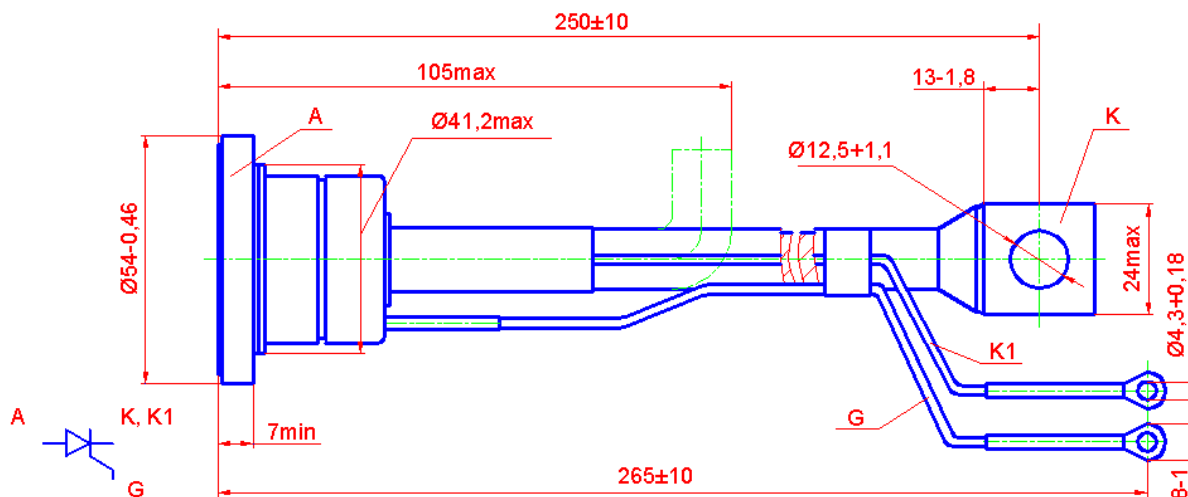
CHARACTERISTICS

Symbols and parameters		Units	TFI271C-200	Conditions
I_L	Latching current	A	5	$T_{vj}=25^{\circ}\text{C}, U_D=12\text{V}$ Gate pulse : 10V, 5 Ω , 1 μs rise time, 10 μs
I_H	Holding current	A	0,3	$T_{vj}=25^{\circ}\text{C}, U_D=12\text{V}$, Gate open
U_{GT}	Gate trigger direct voltage	V	2,5 5,0	$T_{vj}=25^{\circ}\text{C}$, $T_{vj}=-60^{\circ}\text{C}$ $U_D=12\text{V}$
I_{GT}	Gate trigger direct current	A	0,3 0,85	$T_{vj}=25^{\circ}\text{C}$, $T_{vj}=-60^{\circ}\text{C}$
U_{GD}	Gate non-trigger direct voltage	V	0,25	$T_{vj}=125^{\circ}\text{C}$, $U_D = 0,67 U_{DRM}$
I_{GD}	Gate non-trigger direct current	mA	10	Direct gate current
tgd	Delay time	μs	1,6	$T_{vj}=25^{\circ}\text{C}, U_D=500\text{V}$ $I_{TM} = 200 \text{ A}$
tgt	Turn-on time	μs	2,5	Gate pulse : 10V, 5 Ω , 1 μs rise time, 10 μs
tq	Turn-off time	μs	16÷32 20÷40	$T_{vj}=125^{\circ}\text{C}$, $I_{TM}=200 \text{ A}$ $di_R/dt = 10 \text{ A}/\mu\text{s}$, $U_R=100\text{V}$ $U_D = 0,67 U_{DRM}$ $du_D/dt=50 \text{ V}/\mu\text{s}$ $du_D/dt=200 \text{ V}/\mu\text{s}$
Qrr	Recovered charge	μC	300	
trr	Reverse recovery time	μs	4,6	$T_{vj}=125^{\circ}\text{C}$, $I_{TM}=200 \text{ A}$
Irrm	Peak reverse recovery current	A	130	$di_R/dt = 50 \text{ A}/\mu\text{s}$, $U_R=100\text{V}$
(du_D/dt)crit	Critical rate of rise of off-state voltage	V/ μs	500 1000	$T_{vj}=125^{\circ}\text{C}$, $U_D = 0,67 U_{DRM}$ Gate open
Rthjc	Thermal resistance junction to case	$^{\circ}\text{C}/\text{W}$	0,075	Direct current

ORDERING

	TFI	271	C	200	14	7	6	3	
	1	2	3	4	5	6	7	8	

1. Fast thyristor with interdigitated gate structure.
2. Design version.
3. Flat-base (anode).
4. Mean on-state current, A.
5. Voltage code (14=1400 V).
6. Critical rate of rise of off-state voltage ($6 \geq 500 \text{ V}/\mu\text{s}$, $7 \geq 1000 \text{ V}/\mu\text{s}$).
7. Group of turn-off time ($du_D/dt=50 \text{ V}/\mu\text{s}$, $4 \leq 32 \mu\text{s}$, $5 \leq 25\mu\text{s}$, $6 \leq 20 \mu\text{s}$, $7 \leq 16 \mu\text{s}$).
8. Group of turn-on time ($3 \leq 2,5 \mu\text{s}$).



Mounting force : 5 ÷ 7 kN

Weight : 500 grams